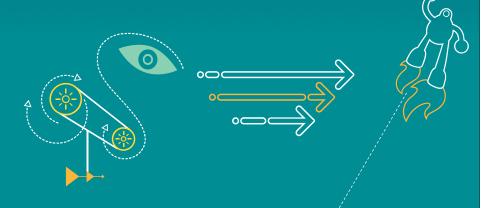
高通硬件基带技术期刊2015-11-09

QUALCOMM°

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Revision History

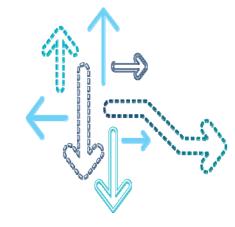
Revision	Date	Description	
А	Nov 2015	Initial release	

Note: There is no Rev. I, O, Q, S, X, or Z per Mil. standards.

Contents

- Baseband
- audio
- PMIC and SMB

Baseband

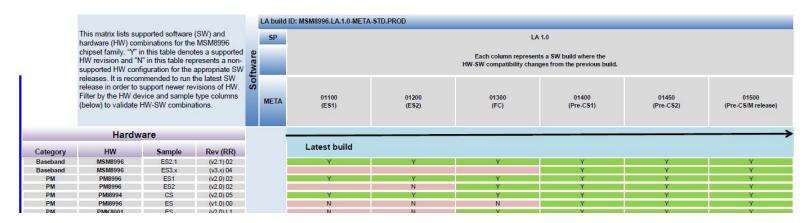


PMI8996 support on MSM8996

适用平台: MSM8996

问题描述: QCOM release的软件可以从01400 (Pre-CS1)支持PMI8996, 请参考

80-NT204-600



PMI8996 和PMI8994 是Pin to Pin兼容的, 元器件的区别请参考原理图80-NT204-41中的BOM表

	Component	L44	C528	C530	C416
83_	PMI8994	DFE252012F-1R0M or CIGT252010EH1R0MNE	2.2uF	2.2uF	1.5nF for AMOLED 47nF for LCD
	PMI8996	CIGT252010EH1R0MNE	4.7uF	4.7uF	1.5nF

地磁传感器布局检查

问题描述:

地磁传感器是敏感部件, 手机上含有很多对地磁传感器数据产生干扰的材料和器件, 如果在板子设计前期不完善(没有跟地磁干扰源保持足够安全距离), 项目后期将很难进行更改, 板子上常见的干扰源情况:

硬磁干扰, 硬磁随距离增加而成指数级衰减, 手机中典型硬磁干扰器件:

扬声器,接收机,自动对焦相机,振动器,霍尔开关 软磁干扰,软磁对磁场影响呈各向异性,典型的软磁效应的零件:

铁质螺钉,屏蔽罩(根据材料),NFC的铁氧天线,Wacom sheet,无线充电磁板 动态干扰,主要是变化的电流导致的,大电流伴随着较大的变化量,电流导致的磁场干扰无规律可言,不能通过软件消除,唯一避免的方式是保持安全距离

解决办法:

在项目硬件初期就联系地磁传感器供应商,获取地磁传感器布局的标准文档,并与地磁传感器供应商一起检查地磁传感器周边的布局;在早期硬件版本回来后,及时联系供应商检查传感器数据,扫描地磁传感器周边的磁干扰情况,尽早发现地磁干扰问题

地磁传感器布局检查(续)

可以在第一版硬件回来后组装2台以上的完整机器(包含最终产品将要用到的磁性材料如NFC,无线充电,各种卡槽屏蔽罩等)以便测试指南针的准确性和机器间的差异性;

常用测试用例:

开关LCD

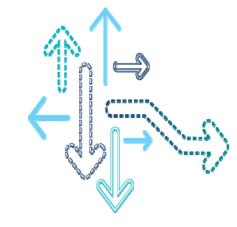
插拔充电器

开关WIFI

开关外放SPEAKER

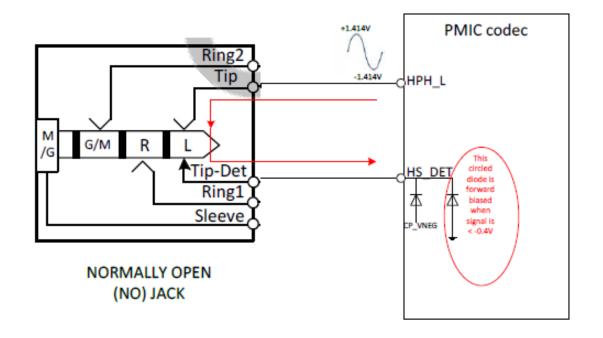
固定手机方位,通过将CPU满载或者手机充电的方法使手机升温,观察方向漂移 固定手机方位,手动使CPU满载/空载,观察方向抖动。地磁传感器是敏感部件,手机上含有很多对地磁传感器数据产生

Audio



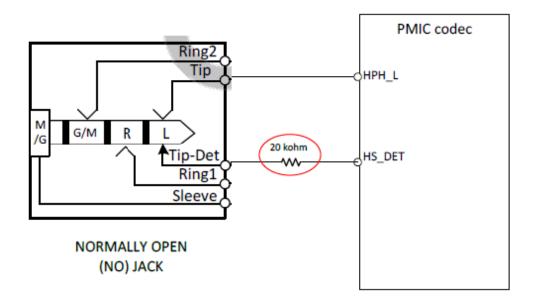
PMIC HS_DET affects THD of HPH_L with NO jack

- 适用平台: PM8909/8916/8952/8956
- 问题描述:在使用常开耳机座时,如果HPH的输出超过500mVrms,HS_DET 将会较明显的影响到左声道 THD+N
- Root cause, 当左声道输出小于约-0.4V时, HS_DET 电路里的二极管将会导通,从而导致有从HS_DET到 地的漏电路径,这个非线性的漏电流会影响左声道的THD+N性能



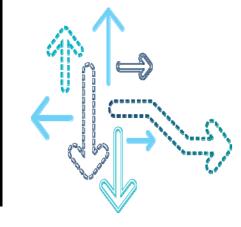
PMIC HS_DET affects THD of HPH_L with NO jack

• Workaround,在HS_DET路径上面串联20Kohm电阻。



问题详细描述请参考文档<80-NT390-13>

PMIC



PMI8996/PMI8994 unused pin handle of 5V boost

适用平台: MSM8996/MSM8994

问题描述:5V boost unused pin handle update

Please connect FB_5V_BST to VREG_5V_BST together and then leave NC if not use 5V boost, we will update following table in next version doc

ADD_R21_RAL	-	-					
5 V boost SMPS	5 V boost SMPS						
VSW_5V_BST	NC	NC	If 5 V boost module unused completely				
VREG_5V_BST	NC	NC					
FB_5V_BST	NC	NC					
REQ_5V_BST	GND	GND	This feature can be specifically unused				